

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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| Applicants: | Charles W. Schietinger et al. | | |
| Title: | Optical Techniques for Measuring Layer Thicknesses and Other Surface Characteristics of Objects Such as Semiconductor Wafers | | |
| Application No.: | Unassigned | Filing Date: | Herewith |
| Examiner: | Unassigned | Group Art Unit: | Unassigned |
| Docket No.: | LUXT.118US2 | Conf. No.: | Unassigned |

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

PRELIMINARY AMENDMENT

Dear Sir:

Please amend the above-identified continuation application with which this Preliminary Amendment is being filed, as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims, which begins on page 3 of this paper.

Remarks begin on page 12 of this paper.

Attorney Docket No.: LUXT.118US2

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